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Details

Product Status	Active
Core Processor	STM8
Core Size	8-Bit
Speed	16MHz
Connectivity	I ² C, IrDA, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, DMA, IR, POR, PWM, WDT
Number of I/O	54
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	1K x 8
RAM Size	2K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.6V
Data Converters	A/D 28x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm8l151r6t6tr

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1 Introduction

This document describes the features, pinout, mechanical data and ordering information for: devices.

- **High-density STM8L15xxx devices:** STM8L151x8 and STM8L152x8 microcontrollers with a Flash memory density of 64 Kbyte.
- **Medium+ density STM8L15xxx devices:** STM8L151R6 and STM8L152R6 microcontrollers with Flash memory density of 32 Kbyte.

For further details on the STMicroelectronics ultra-low-power family please refer to [Section 2.3: Ultra-low-power continuum on page 12](#).

For detailed information on device operation and registers, refer to the reference manual (RM0031).

For information on to the Flash program memory and data EEPROM, refer to the programming manual (PM0054).

For information on the debug module and SWIM (single wire interface module), refer to the STM8 SWIM communication protocol and debug module user manual (UM0470).

For information on the STM8 core, refer to the STM8 CPU programming manual (PM0044).

2 Description

The high-density and medium+ density STM8L15xx6/8 ultra-low-power devices feature an enhanced STM8 CPU core providing increased processing power (up to 16 MIPS at 16 MHz) while maintaining the advantages of a CISC architecture with improved code density, a 24-bit linear addressing space and an optimized architecture for low-power operations.

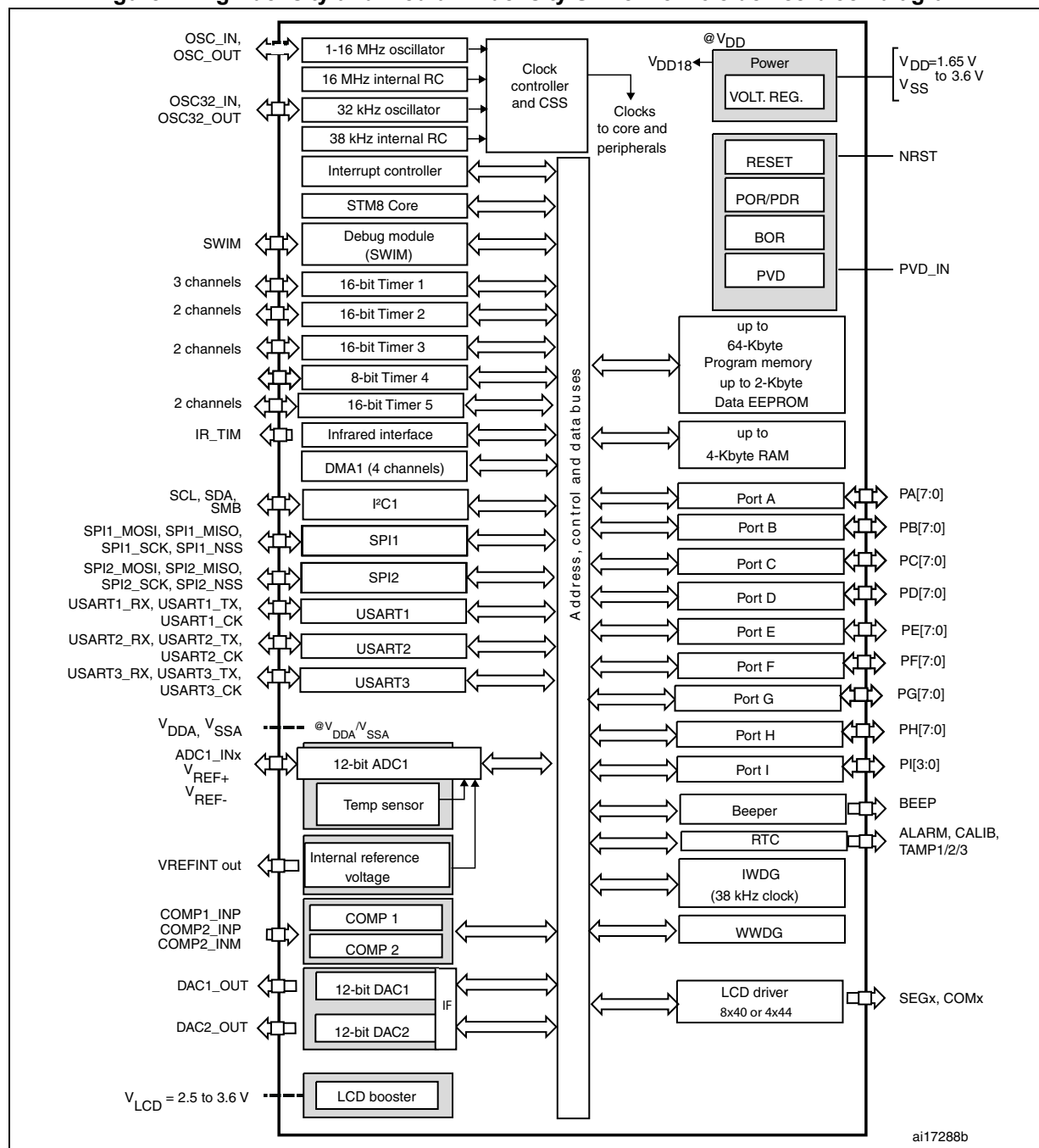
The family includes an integrated debug module with a hardware interface (SWIM) which allows non-intrusive in-application debugging and ultrafast Flash programming.

All high-density and medium+ density STM8L15xx6/8 microcontrollers feature embedded data EEPROM and low-power low-voltage single-supply program Flash memory.

The devices incorporate an extensive range of enhanced I/Os and peripherals, a 12-bit ADC, two DACs, two comparators, a real-time clock, four 16-bit timers, one 8-bit timer, as well as standard communication interfaces such as two SPIs, an I²C interface, and three USARTs. A 8x40 or 4x44-segment LCD is available on the STM8L152x8 devices. The modular design of the peripheral set allows the same peripherals to be found in different ST microcontroller families including 32-bit families. This makes any transition to a different family very easy, and simplified even more by the use of a common set of development tools.

3 Functional overview

Figure 1. High-density and medium+ density STM8L15xx6/8 device block diagram



1. **Legend:**

AF: alternate function
 ADC: Analog-to-digital converter
 BOR: Brownout reset
 DMA: Direct memory access
 DAC: Digital-to-analog converter
 I²C: Inter-integrated circuit multimaster interface
 IWDG: Independent watchdog

3.3 Reset and supply management

3.3.1 Power supply scheme

The device requires a 1.65 V to 3.6 V operating supply voltage (V_{DD}). The external power supply pins must be connected as follows:

- V_{SS1} , V_{DD1} , V_{SS2} , V_{DD2} , V_{SS3} , V_{DD3} , V_{SS4} , V_{DD4} = 1.65 to 3.6 V: external power supply for I/Os and for the internal regulator. Provided externally through V_{DD} pins, the corresponding ground pin is V_{SS} . $V_{SS1}/V_{SS2}/V_{SS3}/V_{SS4}$ and $V_{DD1}/V_{DD2}/V_{DD3}/V_{DD4}$ must not be left unconnected.
- V_{SSA} , V_{DDA} = 1.65 to 3.6 V: external power supplies for analog peripherals (minimum voltage to be applied to V_{DDA} is 1.8 V when the ADC1 is used). V_{DDA} and V_{SSA} must be connected to V_{DD} and V_{SS} , respectively.
- V_{REF+} , V_{REF-} (for ADC1): external reference voltage for ADC1. Must be provided externally through V_{REF+} and V_{REF-} pin.
- V_{REF+} (for DAC1/2): external voltage reference for DAC1 and DAC2 must be provided externally through V_{REF+} .

3.3.2 Power supply supervisor

The device has an integrated ZEROPOWER power-on reset (POR)/power-down reset (PDR). For the device sales types without the “D” option (see [Section 11: Ordering information scheme](#)), it is coupled with a brownout reset (BOR) circuitry. In that case the device operates between 1.8 and 3.6 V, BOR is always active and ensures proper operation starting from 1.8 V. After the 1.8 V BOR threshold is reached, the option byte loading process starts, either to confirm or modify default thresholds, or to disable BOR permanently (in which case, the V_{DD} min. value at power-down is 1.65 V).

Five BOR thresholds are available through option bytes, starting from 1.8 V to 3 V. To reduce the power consumption in Halt mode, it is possible to automatically switch off the internal reference voltage (and consequently the BOR) in Halt mode. The device remains in reset state when V_{DD} is below a specified threshold, $V_{POR/PDR}$ or V_{BOR} , without the need for any external reset circuit.

Note: *For device sales types with the “D” option (see [Section 11: Ordering information scheme](#)) BOR is permanently disabled and the device operates between 1.65 and 3.6 V. In this case it is not possible to enable BOR through the option bytes.*

The device features an embedded programmable voltage detector (PVD) that monitors the V_{DD}/V_{DDA} power supply and compares it to the V_{PVD} threshold. This PVD offers 7 different levels between 1.85 V and 3.05 V, chosen by software, with a step around 200 mV. An interrupt can be generated when V_{DD}/V_{DDA} drops below the V_{PVD} threshold and/or when V_{DD}/V_{DDA} is higher than the V_{PVD} threshold. The interrupt service routine can then generate a warning message and/or put the MCU into a safe state. The PVD is enabled by software.

3.14.1 16-bit advanced control timer (TIM1)

This is a high-end timer designed for a wide range of control applications. With its complementary outputs, dead-time control and center-aligned PWM capability, the field of applications is extended to motor control, lighting and half-bridge driver.

- 16-bit up, down and up/down autoreload counter with 16-bit prescaler
- 3 independent capture/compare channels (CAPCOM) configurable as input capture, output compare, PWM generation (edge and center aligned mode) and single pulse mode output
- 1 additional capture/compare channel which is not connected to an external I/O
- Synchronization module to control the timer with external signals
- Break input to force timer outputs into a defined state
- 3 complementary outputs with adjustable dead time
- Encoder mode
- Interrupt capability on various events (capture, compare, overflow, break, trigger)

3.14.2 16-bit general purpose timers (TIM2, TIM3, TIM5)

- 16-bit autoreload (AR) up/down-counter
- 7-bit prescaler adjustable to fixed power of 2 ratios (1...128)
- 2 individually configurable capture/compare channels
- PWM mode
- Interrupt capability on various events (capture, compare, overflow, break, trigger)
- Synchronization with other timers or external signals (external clock, reset, trigger and enable)

3.14.3 8-bit basic timer (TIM4)

The 8-bit timer consists of an 8-bit up auto-reload counter driven by a programmable prescaler. It can be used for timebase generation with interrupt generation on timer overflow or for DAC trigger generation.

3.15 Watchdog timers

The watchdog system is based on two independent timers providing maximum security to the applications.

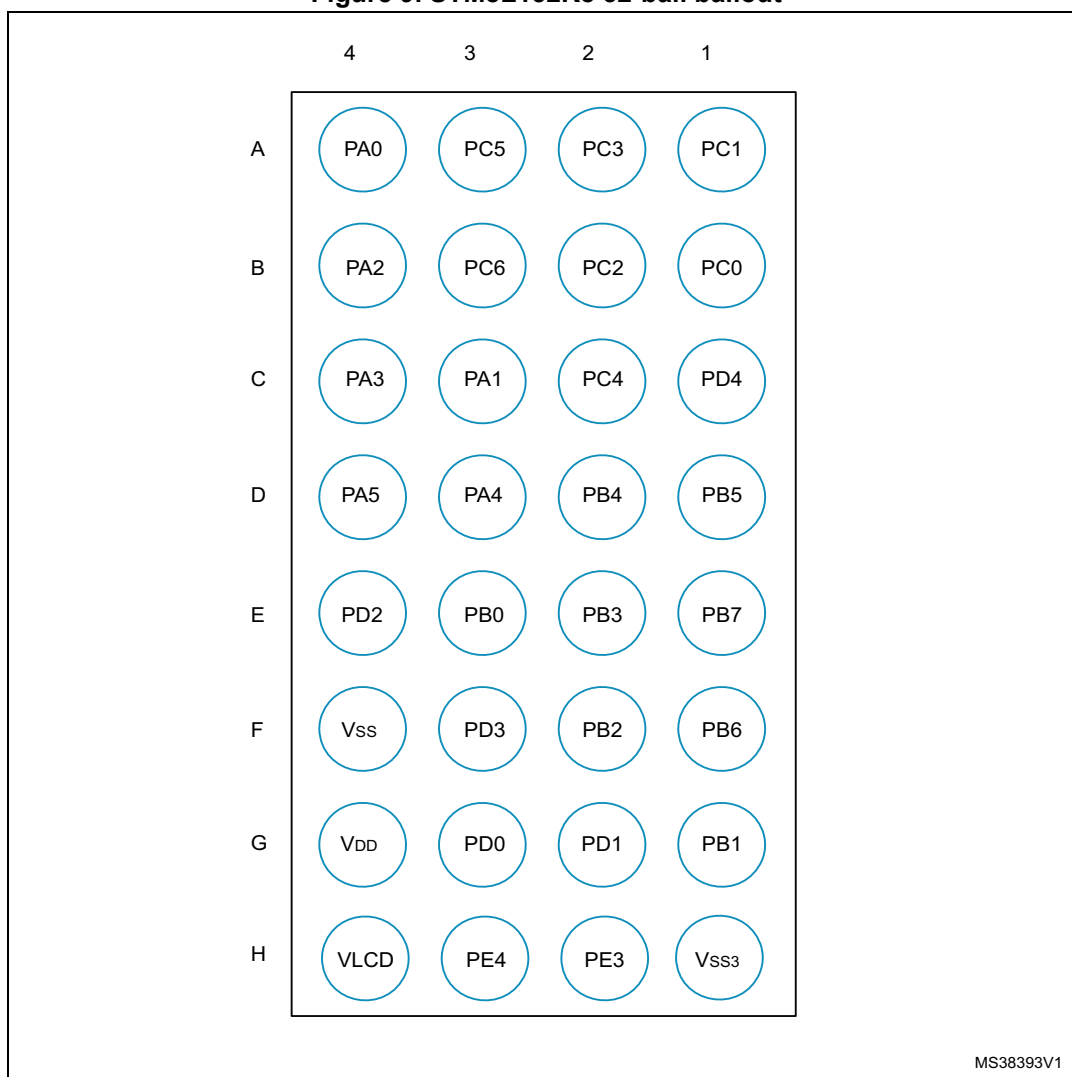
3.15.1 Window watchdog timer

The window watchdog (WWDG) is used to detect the occurrence of a software fault, usually generated by external interferences or by unexpected logical conditions, which cause the application program to abandon its normal sequence.

3.15.2 Independent watchdog timer

The independent watchdog peripheral (IWDG) can be used to resolve processor malfunctions due to hardware or software failures.

Figure 9. STM8L152K8 32-ball ballout



Warning: For the 32-pin STM8L152K8 devices, some active I/O pins are not bonded out of the package. Effectively, all ports available on 48-pin devices must be considered as active ports also for 32-pin devices - see [Table 5: High-density and medium+ density STM8L15x pin description](#) for more details. To avoid spurious effects, users have to configure active ports as input pull-up. A small increase in consumption (typ. < 300 μ A) may occur during the power up and reset phase until these ports are properly configured.

Table 4. Legend/abbreviation

Type	I= input, O = output, S = power supply	
Level	FT: Five-volt tolerant	
	Output	HS = high sink/source (20 mA)
Port and control configuration	Input	float = floating, wpu = weak pull-up
	Output	T = true open drain, OD = open drain, PP = push pull
Reset state	Bold X (pin state after reset release). Unless otherwise specified, the pin state is the same during the reset phase (i.e. "under reset") and after internal reset release (i.e. at reset state).	

Table 5. High-density and medium+ density STM8L15x pin description

Pin number				Pin name	Type	I/O level	Input			Output			Main function (after reset)	Default alternate function
LQFP80	LQFP64	UFQFPN48 and LQFP48	WLCSP32				floating	wpu	Ext. interrupt	High sink/source	OD	PP		
1	-	-	-	PH0/LCD SEG 36 ⁽³⁾	I/O	FT ⁽⁶⁾	X	X	X	HS	X	X	Port H0	LCD segment 36
2	-	-	-	PH1/LCD SEG 37 ⁽³⁾	I/O	FT ⁽⁶⁾	X	X	X	HS	X	X	Port H1	LCD segment 37
3	-	-	-	PH2/LCD SEG 38 ⁽³⁾	I/O	FT ⁽⁶⁾	X	X	X	HS	X	X	Port H2	LCD segment 38
4	-	-	-	PH3/LCD SEG 39 ⁽³⁾	I/O	FT ⁽⁶⁾	X	X	X	HS	X	X	Port H3	LCD segment 39
6	2	2	C3	NRST/PA1 ⁽¹⁾	I/O	-	-	X		HS	-	X	Reset	PA1
7	3	3	B4	PA2/OSC_IN/ [USART1_TX] ⁽²⁾ / [SPI1_MISO] ⁽²⁾	I/O	-	X	X	X	HS	X	X	Port A2	HSE oscillator input / [USART1 transmit] / [SPI1 master in- slave out] /
8	4	4	C4	PA3/OSC_OUT/ [USART1_RX] ⁽²⁾ / [SPI1_MOSI] ⁽²⁾	I/O	-	X	X	X	HS	X	X	Port A3	HSE oscillator output / [USART1 receive] / [SPI1 master out/slave in]
9	5	5	D3	PA4/TIM2_BKIN/ [TIM2_ETR] ⁽²⁾ / LCD_COM0 ⁽³⁾ /ADC1_IN2 [COMP1_INP]	I/O	FT ⁽⁶⁾	X	X	X	HS	X	X	Port A4	Timer 2 - break input / [Timer 2 - trigger] / LCD_COM 0 / ADC1 input 2 / [Comparator 1 positive input]
10	6	6	D4	PA5/TIM3_BKIN/ [TIM3_ETR] ⁽²⁾ / LCD_COM1 ⁽³⁾ /ADC1_IN1/ [COMP1_INP]	I/O	FT ⁽⁶⁾	X	X	X	HS	X	X	Port A5	Timer 3 - break input / [Timer 3 - trigger] / LCD_COM 1 / ADC1 input 1 / [Comparator 1 positive input]

Table 9. General hardware register map (continued)

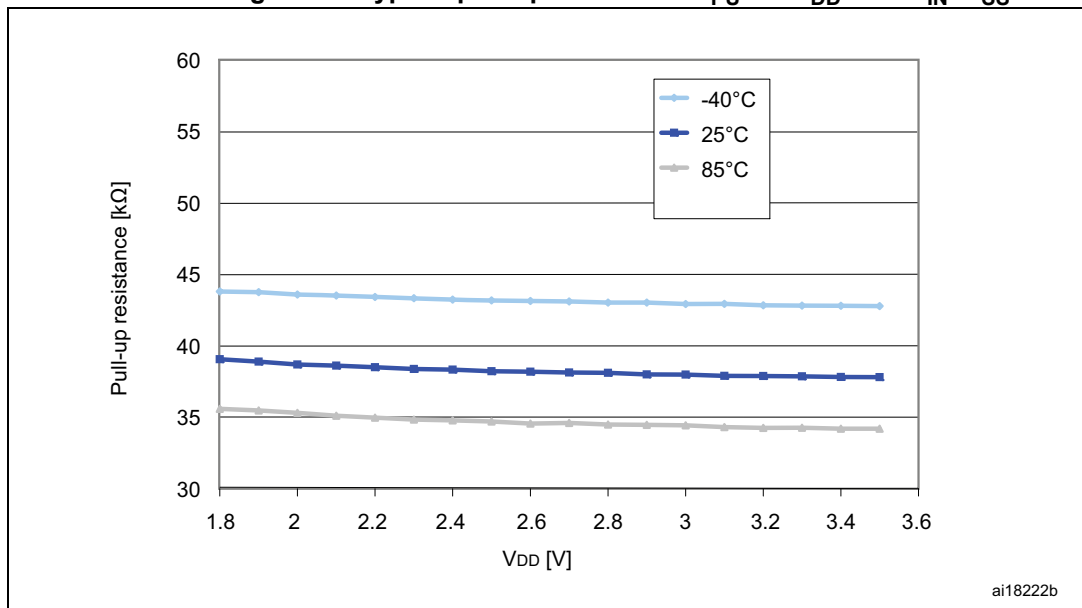
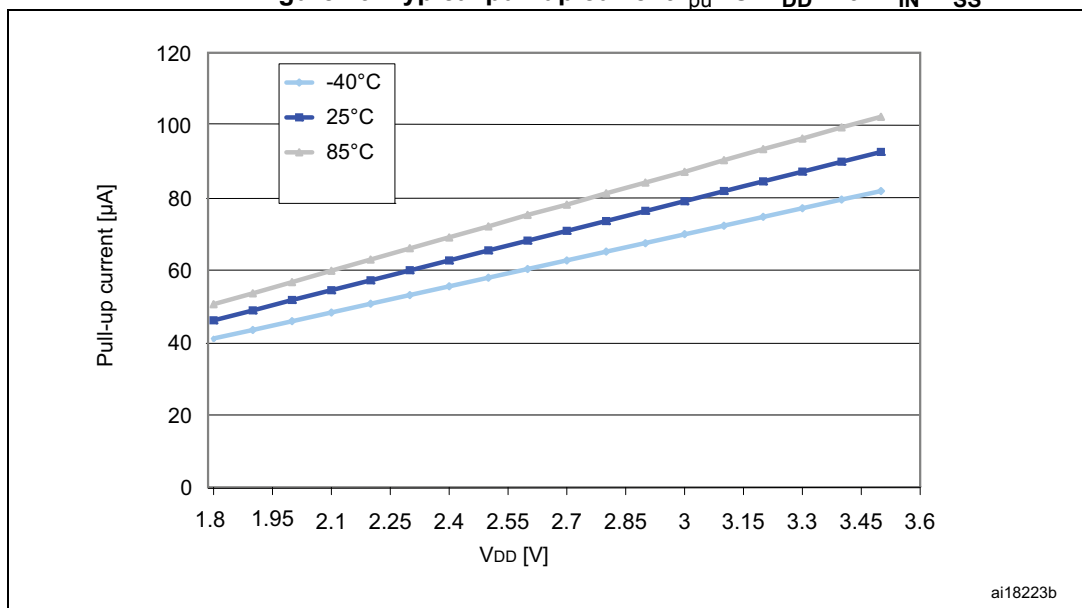
Address	Block	Register label	Register name	Reset status
0x00 509D	SYSCFG	SYSCFG_RMPCR3	Remapping register 3	0x00
0x00 509E		SYSCFG_RMPCR1	Remapping register 1	0x00
0x00 509F		SYSCFG_RMPCR2	Remapping register 2	0x00
0x00 50A0	ITC - EXTI	EXTI_CR1	External interrupt control register 1	0x00
0x00 50A1		EXTI_CR2	External interrupt control register 2	0x00
0x00 50A2		EXTI_CR3	External interrupt control register 3	0x00
0x00 50A3		EXTI_SR1	External interrupt status register 1	0x00
0x00 50A4		EXTI_SR2	External interrupt status register 2	0x00
0x00 50A5		EXTI_CONF1	External interrupt port select register 1	0x00
0x00 50A6	WFE	WFE_CR1	WFE control register 1	0x00
0x00 50A7		WFE_CR2	WFE control register 2	0x00
0x00 50A8		WFE_CR3	WFE control register 3	0x00
0x00 50A9		WFE_CR4	WFE control register 4	0x00
0x00 50AA	ITC - EXTI	EXTI_CR4	External interrupt control register 4	0x00
0x00 50AB		EXTI_CONF2	External interrupt port select register 2	0x00
0x00 50A9 to 0x00 50AF	Reserved area (7 byte)			
0x00 50B0	RST	RST_CR	Reset control register	0x00
0x00 50B1		RST_SR	Reset status register	0x01
0x00 50B2	PWR	PWR_CSR1	Power control and status register 1	0x00
0x00 50B3		PWR_CSR2	Power control and status register 2	0x00
0x00 50B4 to 0x00 50BF	Reserved area (12 byte)			
0x00 50C0	CLK	CLK_CKDIVR	Clock master divider register	0x03
0x00 50C1		CLK_CRTCRR	Clock RTC register	0x00 ⁽¹⁾
0x00 50C2		CLK_ICKCR	Internal clock control register	0x11
0x00 50C3		CLK_PCKENR1	Peripheral clock gating register 1	0x00
0x00 50C4		CLK_PCKENR2	Peripheral clock gating register 2	0x00
0x00 50C5		CLK_CCOR	Configurable clock control register	0x00
0x00 50C6		CLK_ECKCR	External clock control register	0x00
0x00 50C7		CLK_SCSR	System clock status register	0x01
0x00 50C8		CLK_SWR	System clock switch register	0x01
0x00 50C9		CLK_SWCR	Clock switch control register	0xX0

Table 9. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 521F to 0x00 522F	Reserved area (17 byte)			
0x00 5230	USART1	USART1_SR	USART1 status register	0xC0
0x00 5231		USART1_DR	USART1 data register	0xFF
0x00 5232		USART1_BRR1	USART1 baud rate register 1	0x00
0x00 5233		USART1_BRR2	USART1 baud rate register 2	0x00
0x00 5234		USART1_CR1	USART1 control register 1	0x00
0x00 5235		USART1_CR2	USART1 control register 2	0x00
0x00 5236		USART1_CR3	USART1 control register 3	0x00
0x00 5237		USART1_CR4	USART1 control register 4	0x00
0x00 5238		USART1_CR5	USART1 control register 5	0x00
0x00 5239		USART1_GTR	USART1 guard time register	0x00
0x00 523A		USART1_PSCR	USART1 prescaler register	0x00
0x00 523B to 0x00 524F	Reserved area (21 byte)			
0x00 5250	TIM2	TIM2_CR1	TIM2 control register 1	0x00
0x00 5251		TIM2_CR2	TIM2 control register 2	0x00
0x00 5252		TIM2_SMCR	TIM2 Slave mode control register	0x00
0x00 5253		TIM2_ETR	TIM2 external trigger register	0x00
0x00 5254		TIM2_DER	TIM2 DMA1 request enable register	0x00
0x00 5255		TIM2_IER	TIM2 interrupt enable register	0x00
0x00 5256		TIM2_SR1	TIM2 status register 1	0x00
0x00 5257		TIM2_SR2	TIM2 status register 2	0x00
0x00 5258		TIM2_EGR	TIM2 event generation register	0x00
0x00 5259		TIM2_CCMR1	TIM2 capture/compare mode register 1	0x00
0x00 525A		TIM2_CCMR2	TIM2 capture/compare mode register 2	0x00
0x00 525B		TIM2_CCER1	TIM2 capture/compare enable register 1	0x00
0x00 525C		TIM2_CNTRH	TIM2 counter high	0x00
0x00 525D		TIM2_CNTRL	TIM2 counter low	0x00
0x00 525E		TIM2_PSCR	TIM2 prescaler register	0x00
0x00 525F		TIM2_ARRH	TIM2 auto-reload register high	0xFF
0x00 5260		TIM2_ARRL	TIM2 auto-reload register low	0xFF
0x00 5261		TIM2_CCR1H	TIM2 capture/compare register 1 high	0x00

Table 9. General hardware register map (continued)

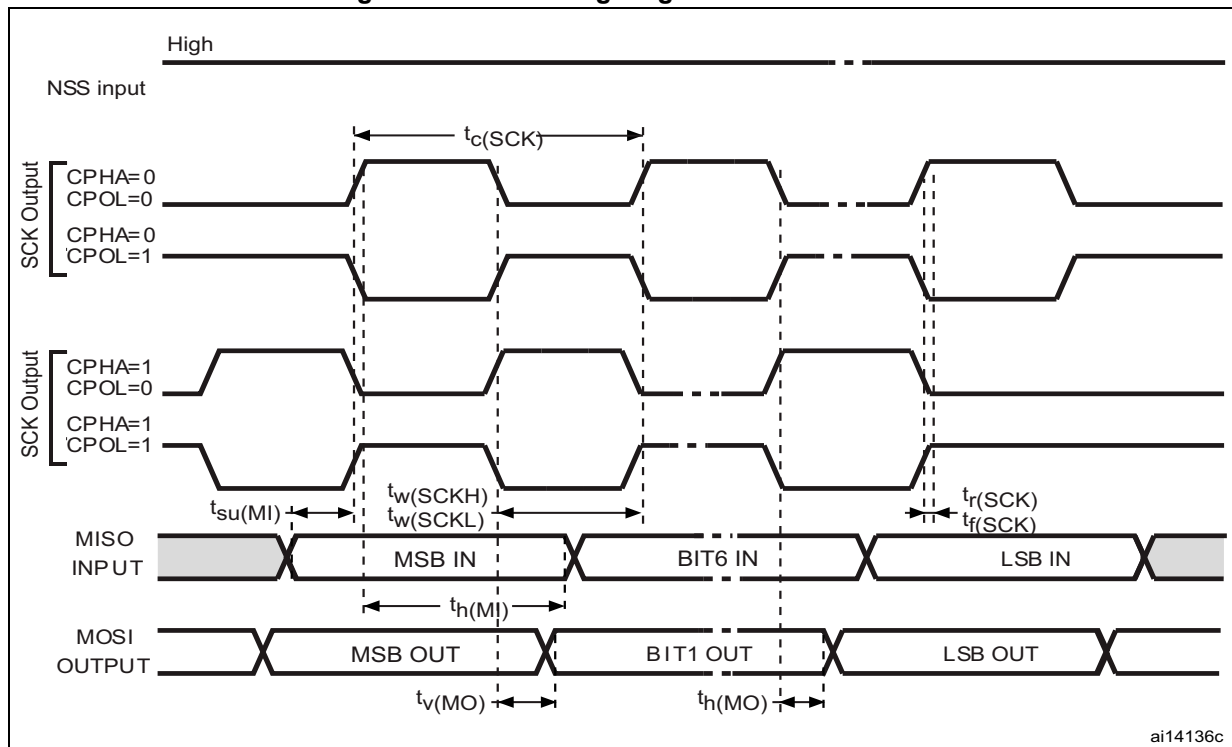
Address	Block	Register label	Register name	Reset status
0x00 5262	TIM2	TIM2_CCR1L	TIM2 capture/compare register 1 low	0x00
0x00 5263		TIM2_CCR2H	TIM2 capture/compare register 2 high	0x00
0x00 5264		TIM2_CCR2L	TIM2 capture/compare register 2 low	0x00
0x00 5265		TIM2_BKR	TIM2 break register	0x00
0x00 5266		TIM2_OISR	TIM2 output idle state register	0x00
0x00 5267 to 0x00 527F	Reserved area (25 byte)			
0x00 5280	TIM3	TIM3_CR1	TIM3 control register 1	0x00
0x00 5281		TIM3_CR2	TIM3 control register 2	0x00
0x00 5282		TIM3_SMCR	TIM3 Slave mode control register	0x00
0x00 5283		TIM3_ETR	TIM3 external trigger register	0x00
0x00 5284		TIM3_DER	TIM3 DMA1 request enable register	0x00
0x00 5285		TIM3_IER	TIM3 interrupt enable register	0x00
0x00 5286		TIM3_SR1	TIM3 status register 1	0x00
0x00 5287		TIM3_SR2	TIM3 status register 2	0x00
0x00 5288		TIM3_EGR	TIM3 event generation register	0x00
0x00 5289		TIM3_CCMR1	TIM3 Capture/Compare mode register 1	0x00
0x00 528A		TIM3_CCMR2	TIM3 Capture/Compare mode register 2	0x00
0x00 528B		TIM3_CCER1	TIM3 Capture/Compare enable register 1	0x00
0x00 528C		TIM3_CNTRH	TIM3 counter high	0x00
0x00 528D		TIM3_CNTRL	TIM3 counter low	0x00
0x00 528E		TIM3_PSCR	TIM3 prescaler register	0x00
0x00 528F		TIM3_ARRH	TIM3 Auto-reload register high	0xFF
0x00 5290		TIM3_ARRL	TIM3 Auto-reload register low	0xFF
0x00 5291		TIM3_CCR1H	TIM3 Capture/Compare register 1 high	0x00
0x00 5292		TIM3_CCR1L	TIM3 Capture/Compare register 1 low	0x00
0x00 5293		TIM3_CCR2H	TIM3 Capture/Compare register 2 high	0x00
0x00 5294		TIM3_CCR2L	TIM3 Capture/Compare register 2 low	0x00
0x00 5295		TIM3_BKR	TIM3 break register	0x00
0x00 5296		TIM3_OISR	TIM3 output idle state register	0x00
0x00 5297 to 0x00 52AF	Reserved area (25 byte)			

Figure 28. Typical pull-up resistance R_{PU} vs. V_{DD} with $V_{IN}=V_{SS}$ Figure 29. Typical pull-up current I_{PU} vs. V_{DD} with $V_{IN}=V_{SS}$ 

Output driving current

Subject to general operating conditions for V_{DD} and T_A unless otherwise specified.

Figure 41. SPI1 timing diagram - master mode



1. Measurement points are done at CMOS levels: $0.3V_{DD}$ and $0.7V_{DD}$.

9.3.9 LCD controller (STM8L152x6/8 only)

In the following table, data are guaranteed by design.

Table 45. LCD characteristics

Symbol	Parameter	Min.	Typ.	Max.	Unit
V_{LCD}	LCD external voltage	-		3.6	V
V_{LCD0}	LCD internal reference voltage 0	-	2.6	-	
V_{LCD1}	LCD internal reference voltage 1	-	2.7	-	
V_{LCD2}	LCD internal reference voltage 2	-	2.8	-	
V_{LCD3}	LCD internal reference voltage 3	-	3.0	-	
V_{LCD4}	LCD internal reference voltage 4	-	3.1	-	
V_{LCD5}	LCD internal reference voltage 5	-	3.2	-	
V_{LCD6}	LCD internal reference voltage 6	-	3.4	-	
V_{LCD7}	LCD internal reference voltage 7	-	3.5	-	
C_{EXT}	V_{LCD} external capacitance	0.1	1	2	μF
I_{DD}	Supply current ⁽¹⁾ at $V_{DD} = 1.8 V$	-	3	-	μA
	Supply current ⁽¹⁾ at $V_{DD} = 3 V$	-	3	-	
$R_{HN}^{(2)}$	High value resistive network (low drive)	-	6.6	-	$M\Omega$
$R_{LN}^{(3)}$	Low value resistive network (high drive)	-	240	-	$k\Omega$
V_{33}	Segment/Common higher level voltage	-		V_{LCDx}	V
V_{34}	Segment/Common 3/4 level voltage	-	$3/4 V_{LCDx}$	-	
V_{23}	Segment/Common 2/3 level voltage	-	$2/3 V_{LCDx}$	-	
V_{12}	Segment/Common 1/2 level voltage	-	$1/2 V_{LCDx}$	-	
V_{13}	Segment/Common 1/3 level voltage	-	$1/3 V_{LCDx}$	-	
V_{14}	Segment/Common 1/4 level voltage	-	$1/4 V_{LCDx}$	-	
V_0	Segment/Common lowest level voltage	0	-	-	

1. LCD enabled with 3 V internal booster (LCD_CR1 = 0x08), 1/4 duty, 1/3 bias, division ratio= 64, all pixels active, no LCD connected.

2. R_{HN} is the total high value resistive network.

3. R_{LN} is the total low value resistive network.

VLCD external capacitor (STM8L152x6/8 only)

The application can achieve a stabilized LCD reference voltage by connecting an external capacitor C_{EXT} to the V_{LCD} pin. C_{EXT} is specified in [Table 45](#).

9.3.13 12-bit DAC characteristics

In the following table, data are guaranteed by design.

Table 50. DAC characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
V_{DDA}	Analog supply voltage	-	1.8	-	3.6	V
V_{REF+}	Reference supply voltage	-	1.8	-	V_{DDA}	
I_{VREF}	Current consumption on V_{REF+} supply	$V_{REF+} = 3.3$ V, no load, middle code (0x800)	-	130	220	μA
		$V_{REF+} = 3.3$ V, no load, worst code (0x000)	-	220	350	
I_{VDDA}	Current consumption on V_{DDA} supply	$V_{DDA} = 3.3$ V, no load, middle code (0x800)	-	210	320	
		$V_{DDA} = 3.3$ V, no load, worst code (0x000)	-	320	520	
T_A	Temperature range		-40	-	125	$^{\circ}C$
$R_L^{(1)(2)}$	Resistive load	DACOUT buffer ON	5	-	-	$k\Omega$
R_O	Output impedance	DACOUT buffer OFF	-	8	10	$k\Omega$
$C_L^{(3)}$	Capacitive load		-	-	50	pF
DAC_OUT ₍₄₎	DAC_OUT voltage	DACOUT buffer ON	0.2	-	$V_{DDA} - 0.2$	V
		DACOUT buffer OFF	0	-	$V_{REF+} - 1$ LSB	V
$t_{settling}$	Settling time (full scale: for a 12-bit input code transition between the lowest and the highest input codes when DAC_OUT reaches the final value ± 1 LSB)	$R_L \geq 5$ $k\Omega$, $C_L \leq 50$ pF	-	7	12	μs
Update rate	Max frequency for a correct DAC_OUT (@95%) change when small variation of the input code (from code i to i+1LSB).	$R_L \geq 5$ $k\Omega$, $C_L \leq 50$ pF	-	-	1	Msp/s
t_{WAKEUP}	Wakeup time from OFF state. Input code between lowest and highest possible codes.	$R_L \geq 5$ $k\Omega$, $C_L \leq 50$ pF	-	9	15	μs
PSRR+	Power supply rejection ratio (to V_{DDA}) (static DC measurement)	$R_L \geq 5$ $k\Omega$, $C_L \leq 50$ pF	-	-60	-35	dB

1. Resistive load between DACOUT and GNDA

2. Output on PF0 or PF1

3. Capacitive load at DACOUT pin

4. It gives the output excursion of the DAC

9.3.14 12-bit ADC1 characteristics

In the following table, data are guaranteed by design.

Table 53. ADC1 characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
V _{DDA}	Analog supply voltage	-	1.8		3.6	V
V _{REF+}	Reference supply voltage	2.4 V ≤V _{DDA} ≤ 3.6 V	2.4		V _{DDA}	
		1.8 V≤V _{DDA} ≤ 2.4 V	V _{DDA}			
V _{REF-}	Lower reference voltage	-	V _{SSA}			
I _{VDDA}	Current on the V _{DDA} input pin	-	-	1000	1450	μA
I _{VREF+}	Current on the V _{REF+} input pin	-	-	400	700 (peak) ⁽¹⁾	
		-	-		450 (average) ⁽¹⁾	
V _{AIN}	Conversion voltage range	-	0 ⁽²⁾	-	V _{REF+}	
T _A	Temperature range	-	-40	-	125	°C
R _{AIN}	External resistance on V _{AIN}	on PF0/1/2/3 fast channels	-	-	50 ⁽³⁾	kΩ
		on all other channels	-	-		
C _{ADC}	Internal sample and hold capacitor	on PF0/1/2/3 fast channels	-	16	-	pF
		on all other channels	-		-	
f _{ADC}	ADC sampling clock frequency	2.4 V≤V _{DDA} ≤3.6 V without zooming	0.320	-	16	MHz
		1.8 V≤V _{DDA} ≤2.4 V with zooming	0.320	-	8	
f _{CONV}	12-bit conversion rate	V _{AIN} on PF0/1/2/3 fast channels	-	-	1 ⁽³⁾⁽⁴⁾	
		V _{AIN} on all other channels	-	-	760 ⁽³⁾⁽⁴⁾	kHz
f _{TRIG}	External trigger frequency	-	-	-	t _{conv}	1/f _{ADC}
t _{LAT}	External trigger latency	-	-	-	3.5	1/f _{SYSCLK}

In the following three tables, data are guaranteed by characterization result.

Table 54. ADC1 accuracy with $V_{DDA} = 3.3\text{ V}$ to 2.5 V

Symbol	Parameter	Conditions	Typ.	Max.	Unit
DNL	Differential non linearity	f _{ADC} = 16 MHz	1	1.6	LSB
		f _{ADC} = 8 MHz	1	1.6	
		f _{ADC} = 4 MHz	1	1.5	
INL	Integral non linearity	f _{ADC} = 16 MHz	1.2	2	
		f _{ADC} = 8 MHz	1.2	1.8	
		f _{ADC} = 4 MHz	1.2	1.7	
TUE	Total unadjusted error	f _{ADC} = 16 MHz	2.2	3.0	
		f _{ADC} = 8 MHz	1.8	2.5	
		f _{ADC} = 4 MHz	1.8	2.3	
Offset	Offset error	f _{ADC} = 16 MHz	1.5	2	
		f _{ADC} = 8 MHz	1	1.5	
		f _{ADC} = 4 MHz	0.7	1.2	
Gain	Gain error	f _{ADC} = 16 MHz	1	1.5	
		f _{ADC} = 8 MHz			
		f _{ADC} = 4 MHz			

Table 55. ADC1 accuracy with $V_{DDA} = 2.4\text{ V}$ to 3.6 V

Symbol	Parameter	Typ.	Max.	Unit
DNL	Differential non linearity	1	2	LSB
INL	Integral non linearity	1.7	3	
TUE	Total unadjusted error	2	4	
Offset	Offset error	1	2	
Gain	Gain error	1.5	3	

Table 56. ADC1 accuracy with $V_{DDA} = V_{\text{REF}}^+ = 1.8\text{ V}$ to 2.4 V

Symbol	Parameter	Typ.	Max.	Unit
DNL	Differential non linearity	1	2	LSB
INL	Integral non linearity	2	3	
TUE	Total unadjusted error	3	5	
Offset	Offset error	2	3	
Gain	Gain error	2	3	

Electromagnetic interference (EMI)

Based on a simple application running on the product (toggling 2 LEDs through the I/O ports), the product is monitored in terms of emission. This emission test is in line with the norm IEC61967-2 which specifies the board and the loading of each pin.

Table 59. EMI data ⁽¹⁾

Symbol	Parameter	Conditions	Monitored frequency band	Max vs.	Unit
				16 MHz	
S _{EMI}	Peak level	V _{DD} = 3.6 V, T _A = +25 °C, LQFP80 conforming to IEC61967-2	0.1 MHz to 30 MHz	10	dBμV
			30 MHz to 130 MHz	4	
			130 MHz to 1 GHz	1	
			SAE EMI Level	1.5	-

1. Not tested in production.

Absolute maximum ratings (electrical sensitivity)

Based on two different tests (ESD and LU) using specific measurement methods, the product is stressed in order to determine its performance in terms of electrical sensitivity. For more details, refer to the application note AN1181.

Electrostatic discharge (ESD)

Electrostatic discharges (a positive then a negative pulse separated by 1 second) are applied to the pins of each sample according to each pin combination. The sample size depends on the number of supply pins in the device (3 parts*(n+1) supply pin). Two models can be simulated: human body model and charge device model. This test conforms to the JESD22-A114A/C101 or ANSI/ESD STM5.3.1 standards.

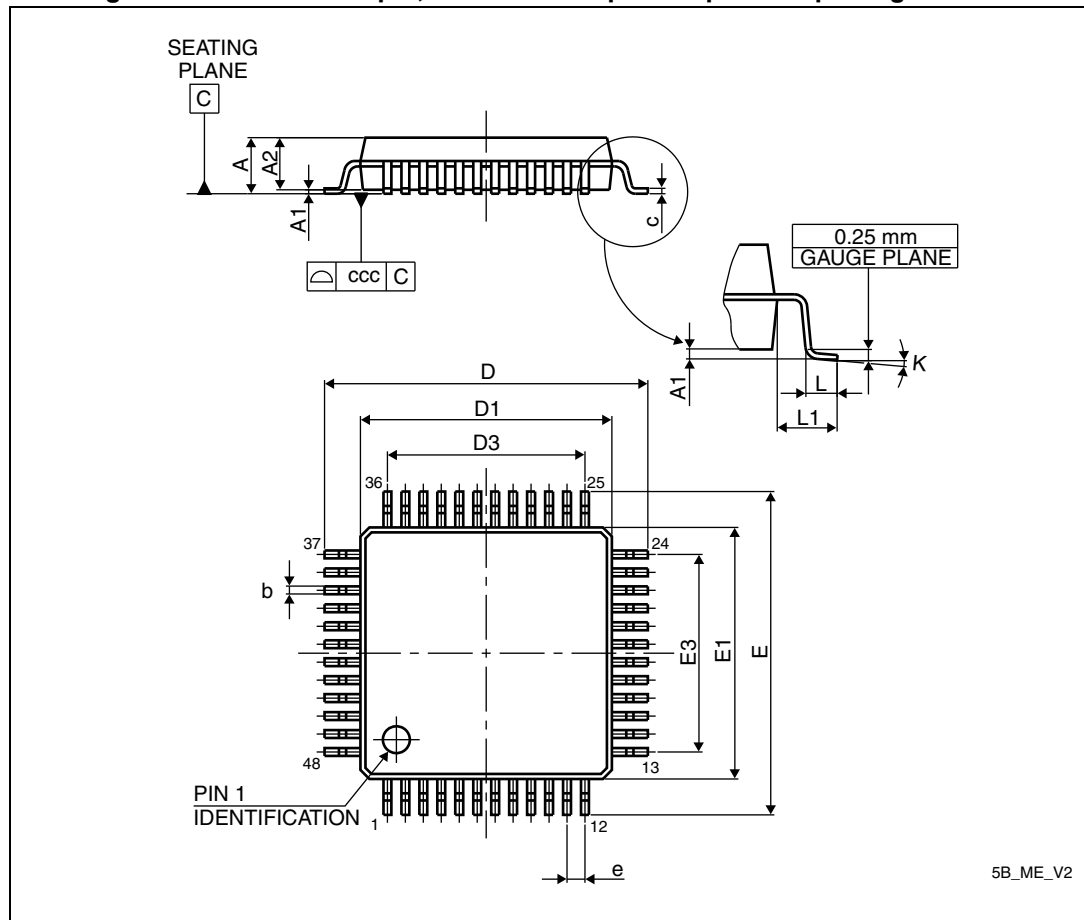
Table 60. ESD absolute maximum ratings

Symbol	Ratings	Conditions	Package	Class	Maximum value ⁽¹⁾	Unit
V _{ESD(HBM)}	Electrostatic discharge voltage (human body model)	T _A = +25 °C, conforming to JESD22-A414	All	2	2000	V
V _{ESD(CDM)}	Electrostatic discharge voltage (charge device model)	T _A = +25 °C, conforming to ANSI/ESD STM5.3.1	WLCSP32	TBD	TBD	
		T _A = +25 °C, conforming to JESD22-C101	All other	II	500	

1. Data based on characterization results.

10.3 LQFP48 package information

Figure 54. LQFP48 - 48-pin, 7 x 7 mm low-profile quad flat package outline



1. Drawing is not to scale.

Table 70. Document revision history (continued)

Date	Revision	Changes
15-Feb-2017	10	Updated value of feature 12-bit synchronized ADC (number of channels) for STM8L15xK8 on Table 2: High-density and medium-density STM8L15xx6/8 low power device features and peripheral counts .